



IN THE U.S. PATENT AND TRADEMARK OFFICE

IPR

Applicant : Satoshi FURUTA

Title : METHOD FOR MANUFACTURE OF ESTERS BY  
TRANSESTERIFICATION

Serial No. : 10/558 935 Group: 1621

Confirmation No.: 6397

Filed : December 1, 2005 Examiner: Katakam

International Application No.: PCT/JP2004/009250

International Filing Date : June 23, 2004

Atty. Docket No.: 4700.P0320US

Commissioner for Patents  
 P.O. Box 1450  
 Alexandria, VA 22313-1450

**FIRST CLASS MAILING CERTIFICATE**

Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service under 37 CFR 1.8 as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on January 11, 2007.




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Correspondence: Information Disclosure Statement  
 dated January 11, 2007  
 including enclosures listed thereon

190.05/05



## PATENT APPLICATION

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January 11, 2007

1/PW

Applicant: Satoshi FURUTA

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**INFORMATION DISCLOSURE STATEMENT**

Sir:

In compliance with the provisions of Rules 1.97(e)(1) and 1.98, enclosed herewith is a copy of the European Patent Office Search Report, Form PTO-1449 and the references cited thereon. The relevance of these references is explained on the enclosed search report. Accordingly, further comment at this point in time should not be necessary.

I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Further consideration is respectfully solicited.

Respectfully submitted,



TFC/smd

Terryence F. Chapman

FLYNN, THIEL, BOUTELL & TANIS, P.C. 2026 Rambling Road Kalamazoo, MI 49008-1631 Phone: (269) 381-1156 Fax: (269) 381-5465	Dale H. Thiel David G. Boutell Terryence F. Chapman Mark L. Maki Liane L. Churney Brian R. Tumm Steven R. Thiel Donald J. Wallace Sidney B. Williams, Jr.	Reg. No. 24 323 Reg. No. 25 072 Reg. No. 32 549 Reg. No. 36 589 Reg. No. 40 694 Reg. No. 36 328 Reg. No. 53 685 Reg. No. 43 977 Reg. No. 24 949
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Encl: Copy of European Patent Office Search Report  
dated October 19, 2006 (3 pages)  
Form PTO-1449 and references cited thereon  
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U.S. PATENT DOCUMENTS			
Examiner Initials*	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA 6 090 959	07-18-2000	HIRANO et al
	AB		
	AC		
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	AE		
	AF		
	AG		
	AH		
	AI		
	AJ		
	AK		

## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AL	EP 1 505 048 A1	02-09-2005	LACOME et al	
	AM				
	AN				
	AO				
	AP				

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AQ	
	AR	
EXAMINER SIGNATURE		DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.